


<b>Search Notes</b>  	<b>Application/Control No.</b>  10559864	<b>Applicant(s)/Patent Under Reexamination</b>  HAIK-BERAUD ET AL.
	<b>Examiner</b>  Ngoc-Yen M Nguyen	<b>Art Unit</b>  1793

SEARCHED			
Class	Subclass	Date	Examiner
423	235,239.1, 248, 245.3, 245.1, 210, 220, 228, 230	3/29/09	NN

SEARCH NOTES		
Search Notes	Date	Examiner
East search	3/29/09	NN
Inventor name search	3/29/09	NN
Update search	11/8/09	NN
Update search	3/24/10	NN
Update search	8/30/10	NN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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